

L Number	Hits	Search Text	DB	Time stamp
-	1148	716/19	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 11:48
-	758	716/21	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 11:48
-	11	(716/19).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 16:46
-	15	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:30
-	1	(716/21).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect\$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:33
-	2	(716/\$).ccls. and (mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect\$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:34
-	13	(mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and (inspect\$ adj data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 13:35
-	2	(mask or reticle) and (CAD same ((electron adj beam) or EB) same data) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:11
-	2	(mask or reticle) and (((electron adj beam) or EB) same data) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:13
-	3	(mask or reticle) and ((data adj conversion) adj error)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 17:20
-	3	(mask or reticle) and ((data adj (translation or conversion) adj error))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:26
-	2	(mask or reticle) and CAD and ((data adj (translation or conversion) adj error))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:27

-	2	(mask or reticle) and CAD and ((data adj (translation or conversion) adj (error or mistake)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:29
-	2	CAD and ((data adj (translation or conversion) adj (error or mistake)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/22 18:30
-	0	(beam adj lithograph) same (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:49
-	0	(beam adj lithograph) and (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:47
-	7	(beam adj lithography) same (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 10:50
-	30	(beam adj lithography) and (inspection adj method)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:38
-	21	(beam adj lithography) and (inspection adj method) and (quality or contrast)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:40
-	2	(beam adj lithography) and ((inspection adj method) same (quality or contrast))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/23 12:42
-	1	(mask or reticle) and ((data adj verification) same (coordinate adj data))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:18
-	4	(mask or reticle) and ((data adj verification) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:36
-	38	(mask or reticle) and ((data adj (check\$ or verification)) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 13:52
-	9	(mask or reticle) and (electron adj beam) and ((data adj (check\$ or verification)) same (coordinate))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:02

-	1	(mask or reticle) and (electron adj beam) and ((data adj (check\$ or verification)) same ((two adj dimension\$) adj (coordinate))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:29
-	0	(mask or reticle) and (electron adj beam) and ((pattern adj (check\$ or verification)) same ((two adj dimension\$) adj (coordinate))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:30
-	1	(mask or reticle) and (electron adj beam) and ((check\$ or verification) same ((two adj dimension\$) adj (coordinate))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:34
-	64	(mask or reticle) and (electron adj beam) and (pattern adj (check\$ or verification))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/09/27 14:34



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